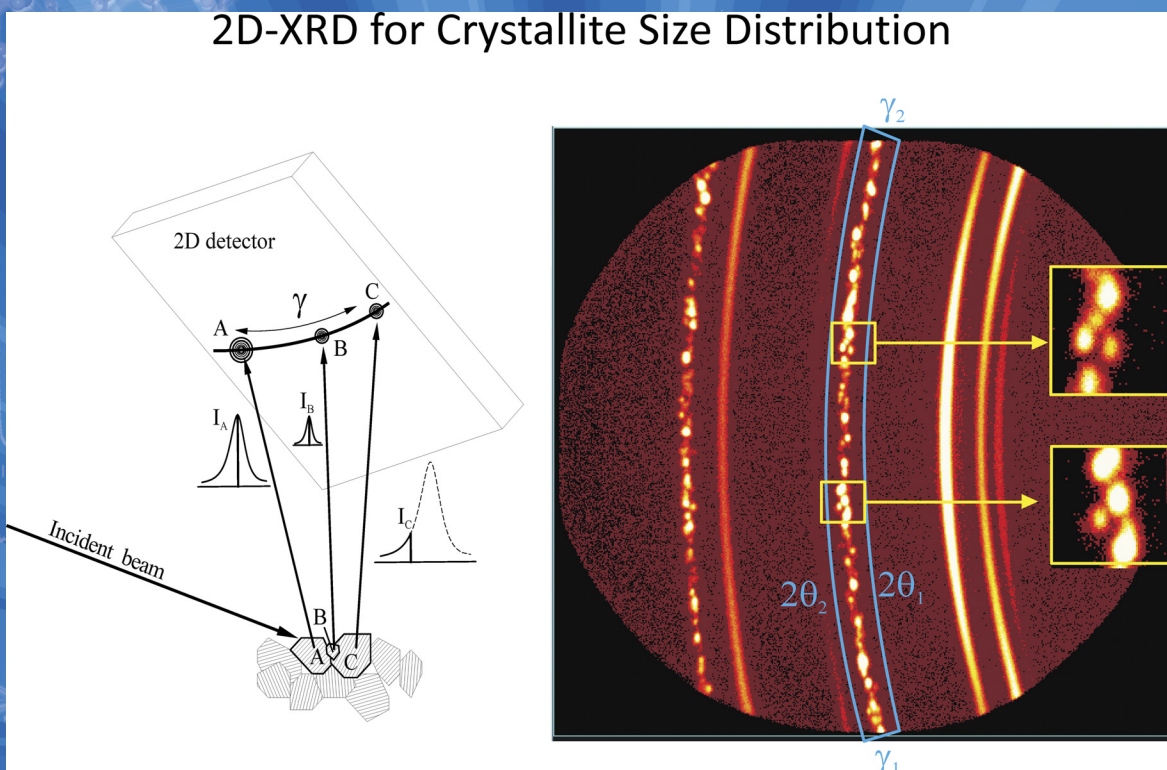


Powder Diffraction PDJ

Journal of Materials Characterization

2D-XRD for Crystallite Size Distribution



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Aims & Scope

ICDD's quarterly, and special topical issue, international journal, *Powder Diffraction*, focuses on materials characterization employing X-ray powder diffraction and related techniques. With feature articles covering a wide range of applications, from mineral analysis to epitaxial growth of thin films to advances in application software and hardware, this journal offers a wide range of practical applications. ICDD, in collaboration with the Denver X-ray Conference Organizing Committee, has increased services for the subscribers of Powder Diffraction and authors of Advances in X-ray Analysis. Beginning in 2006, ICDD offered a copy of the previous year's edition of AXA to Powder Diffraction institutional subscribers who receive both print and on-line versions. This effectively doubles the number of articles annually available to Powder Diffraction subscribers and significantly increases the circulation for the authors in Advances in X-ray Analysis.

Subject coverage includes:

- Techniques and procedures in X-ray powder diffractometry
- Advances in instrumentation
- Study of materials including organic materials, minerals, metals and thin film superconductors
- Publication of powder data on new materials

International Centre for Diffraction Data

The International Centre for Diffraction Data (ICDD[®]) is a non-profit scientific organization dedicated to collecting, editing, publishing, and distributing powder diffraction data for the identification of materials. The membership of the ICDD consists of worldwide representation from academe, government, and industry.

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EDITORIAL

- Camden R. Hubbard Editorial 51
doi:10.1017/S0885715622000227

PROCEEDINGS PAPERS

- Mark A. Rodriguez,
Jamin Pillars, Nichole R.
Valdez, James J. M. Griego,
Matthew V. Gallegos,
John A. Krukar,
Andrew Polonsky and
Steven L. Wolfley Texture and strain analysis of tungsten films via Tilt-A-Whirl methodology 52
doi:10.1017/S0885715622000203
- Tomohiro Shibata Inverse pole figure of CVD coatings of metal cutting tools using an XRD Bragg Brentano geometry 62
doi:10.1017/S0885715622000197
- T. G. Fawcett, J. R. Blanton,
S. N. Kabekkodu,
T. N. Blanton, J. Lyza
and D. Broton Best references for the QPA of Portland cement 68
doi:10.1017/S0885715622000215

INSTRUMENTATION, ANALYSIS AND LABORATORY DEVELOPMENTS

- Bob B. He Crystallite size distribution by two-dimensional XRD 76
doi:10.1017/S0885715622000045

TECHNICAL ARTICLES

- Mayra Guamán-Ayala,
Pablo V. Tuza and
Mariana M. V. M. Souza Cation reducibility of $\text{LaNi}_{0.5}\text{Ti}_{0.5}\text{O}_3$, $\text{LaNi}_{0.5}\text{Ti}_{0.45}\text{Co}_{0.05}\text{O}_3$, and $\text{LaNi}_{0.45}\text{Co}_{0.05}\text{Ti}_{0.5}\text{O}_3$ perovskites from X-ray powder diffraction data using the Rietveld method 84
doi:10.1017/S0885715622000112
- Kaitong Sun, Yinghao Zhu,
Si Wu, Junchao Xia,
Pengfei Zhou, Qian Zhao,
Chongde Cao and
Hai-Feng Li Temperature-dependent structure of an intermetallic ErPd_2Si_2 single crystal: a combined synchrotron and in-house X-ray diffraction study 91
doi:10.1017/S0885715622000100

NEW DIFFRACTION DATA

- James A. Kaduk,
Stacy Gates-Rector and
Thomas N. Blanton Crystal structure of a second polymorph of germacone, $\text{C}_{15}\text{H}_{22}\text{O}$ 98
doi:10.1017/S0885715622000057

DATA REPORTS

- Zhi Qiang Li, Shan Zhai Shang, Xiao Xiang Liao, Ping Lei, Jing Mei Han, Bin Yi, Ji Yang, Qi Yi Zhang, Zi Li Suo and Hui Li X-ray powder diffraction data for nicotine 2,6-dihydroxybenzoate, $C_{10}H_{15}N_2 \cdot C_7H_5O_4$
doi:10.1017/S0885715622000070 105
- Gerzon E. Delgado, Cecilia Chacón, Gustavo Marroquin, Jonathan Cisterna and Iván Brito X-ray powder diffraction data for the second and third polymorphs of 1-methylhydantoin
doi:10.1017/S0885715622000136 108

INTERNATIONAL REPORT

- Fan Zhang TMS 2022 Annual Meeting & Exhibition Report
doi:10.1017/S0885715622000124 115

CALENDARS OF MEETINGS, SHORT COURSES AND WORKSHOPS

- Gang Wang Calendar of Forthcoming Meetings
doi:10.1017/S0885715622000161 117
- Gang Wang Calendar of Short Courses and Workshops
doi:10.1017/S0885715622000173 119

On the Cover: Crystallite size distribution can now be determined via using 2-D detectors and algorithms and methods as presented in Bob He's paper "Crystallite Size Distribution by Two-dimensional XRD". The size distribution information can be obtained when using an appropriate X-ray beam size and a 2-D detector. The left figure shows diagrammatically how the intensity of a spot on the 2D detector is a function of crystallite size and orientation. The right figure show a 2D-diffraction pattern of a sample with large crystallite size. Note the many spots and variation of spots from a constant 2theta ring.

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For the novice with some XRD knowledge or for the experienced with an interest in the theory behind XRD, this clinic offers a strong base for increased lab performance.

The clinic covers instrumentation, specimen preparation, data acquisition and qualitative phase analysis through live demonstrations. It also covers hands-on use of personal computers for demonstration of the latest software including data mining with the Powder Diffraction File (PDF) and use of the powder diffractometer: optical arrangement, factors affecting instrumentation profile width, choice and function of divergence slit, calibration and alignment, detectors, and X-ray optics.

www.icdd.com/xrd



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For the experienced XRD scientist, this session offers enhanced analysis skills through intense problem solving, as well as an introduction to the Rietveld Method. The course emphasizes computer-based methods of data interpretation, both for qualitative and quantitative phase analysis.

The advanced course covers a wide range of topics including systematic errors, factors affecting intensities of diffraction peaks; data reduction algorithms; phase identification; advanced data mining with the PDF and its application in search/match; powder pattern indexing methods; structure solution methods; quantitative phase analysis using both reference intensity ratio (RIR) and Rietveld Method.

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Rietveld Refinement & Indexing Clinic:

Powder pattern indexing and Rietveld structural refinement techniques are complementary and are often combined to determine the structure of a material. Successful indexing of a powder pattern is considered strong evidence for phase purity. Indexing is considered a prelude to determining the crystal structure, and permits phase identification by lattice matching techniques. This clinic introduces the theory and formalisms of various indexing methods and structural refinement techniques along with quantitative analysis. One unique aspect of this clinic is the extensive use of computer laboratory problem solving and exercises that teach method development in a hands-on environment.

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Please note: A minimum of 10 registrants per course is required, otherwise the course will be cancelled and your registration fee will be refunded. You will be notified of a course cancellation no later than two weeks prior to the start of the course.

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